N. C. a. C. D. C. a. a. a. C. C. a. d.	Application/Control No. Applicant(s)/Pater Reexamination JUNG ET AL.		ent Under	
Notice of References Cited	Examiner	Art Unit		
	Mark T. Vogelbacker	3677	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0040288	02-2003	Kang et al.	455/90
*	В	US-2004/0141287	07-2004	Kim et al.	361/683
*	С	US-6,088,240	07-2000	Steinhoff et al.	361/814
*	D	US-2003/0162569	08-2003	Arakawa et al.	455/566
*	ε	US-2005/0032559	02-2005	Sudo et al.	455/575.3
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	j	US-			
	К	US-			
	L	US-			·
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001319833 A	11-2001	Japan	TAMAMITSU et al.	H01G 09/035
	0	KR 20010051282	08-2001	Korea	Samsung Electronics Co.	
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.